Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/552,786	DEPERTHES ET AL.	
Examiner	Art Unit	
l Jae W. Lee, Ph.D.	1656	

	SEARCHED				
Class	Subclass	Date	Examiner		
NONE	NONE	6/5/2007	JWL		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STN databases: BIOSIS, CAPLUS, EMBASE, MEDLINE, SCISEARCH, AND JAPIO, see attached search history printouts	6/5/2007	JWL	
EAST inventor name search	6/5/2007	JWL .	
See search results available by SCORE	6/5/2007	JWL	
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